Power MOSFET and Schottky Diode

-20 V, -3.0 A, Single P-Channel with 3.0 A Schottky Barrier Diode, ChipFET™

Features

- Leadless SMD Package Featuring a MOSFET and Schottky Diode
- 40% Smaller than TSOP-6 Package with Similar Thermal Characteristics
- Independent Pinout to each Device to Ease Circuit Design
- Ultra Low VF Schottky
- Pb–Free Package is Available

Applications

- Li-Ion Battery Charging
- High Side DC-DC Conversion Circuits
- High Side Drive for Small Brushless DC Motors
- Power Management in Portable, Battery Powered Products

MOSFET MAXIMUM RATINGS (T_J = 25°C unless otherwise noted)

Parameter			Symbol	Value	Units
Drain-to-Source Voltage			V _{DSS}	-20	V
Gate-to-Source Volta	age		V_{GS}	±12	V
Continuous Drain	Steady	T _J = 25°C	I _D	-2.2	Α
Current	State	T _J = 85°C	1	-1.6	
	t ≤ 5 s	T _J = 25°C	I _D	-3.0	Α
Pulsed Drain Current	t _p = 10 μs		I _{DM}	-9.0	Α
Power Dissipation	Steauy	$T_J = 25^{\circ}C$	PD	1.1	W
1 to 1/2		State	$T_J = 85^{\circ}C$	Dr.	0.6
CONTRACTOR OF THE PARTY OF THE	t ≤ 5 s	T _J = 25°C	1	2.1	
Continuous Source C	urrent (Bo	dy Diode)	IS	-2.1	Α
Operating Junction and Storage Temperature		T _J , T _{STG}	-55 to 150	°C	
Lead Temperature for (1/8" from case for 10		g Purposes	TL	260	°C

SCHOTTKY DIODE MAXIMUM RATINGS

(T₁ = 25°C unless otherwise noted)

(1) = 20 0 difference floted)								
Parameter			Symbol	Value	Unit			
Peak Repetitive Reve	k Repetitive Reverse Voltage		V _{RRM}	20	V			
DC Blocking Voltage			V_R	20	V			
Average Rectified Forward Current	Steady State	T _J = 25°C	I _F	2.2	Α			
	t ≤ 5 s			3.0	A			

Maximum ratings are those values beyond which device damage can occur. Maximum ratings applied to the device are individual stress limit values (not normal operating conditions) and are not valid simultaneously. If these limits are ceeded device functional operation is not implied, damage may occur and reliability may be affected.



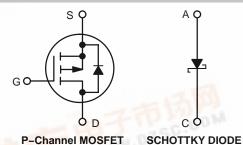
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MOSFET					
V _{(BR)DSS}	R _{DS(on)} TYP	I _D MAX			
–20 V	–130 mΩ @ –4.5 V	-3.0 A			

200 mΩ @ -2.5 V SCHOTTKY DIODE

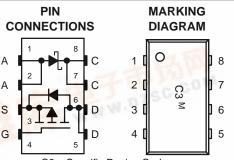
V _R MAX	V _F TYP	I _F MAX
20 V	0.510 V	3.0 A



P-Channel MOSFET



ChipFET **CASE 1206A** STYLE 3



C2 = Specific Device Code M = Month Code

ORDERING INFORMATION

Device	Package	Shipping [†]
NTHD4P02FT1	ChipFET	3000/Tape & Reel
NTHD4P02FT1G	ChipFET (Pb-free)	3000/Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

THERMAL RESISTANCE RATINGS

Parameter			Symbol	Max	Units
Junction-to-Ambient (Note 1)	Steady State	T 250C	$R_{\theta JA}$	110	°C/W
	t ≤ 5 s	T _J = 25°C		60	

^{1.} Surface Mounted on FR4 Board using 1 in sq pad size (Cu area = 1.27 in sq [1 oz] including traces).

$\textbf{MOSFET ELECTRICAL CHARACTERISTICS} \ (T_J = 25^{\circ}\text{C unless otherwise noted})$

Parameter	Symbol	Test Conditions	Min	Тур	Max	Units
OFF CHARACTERISTICS	•		-			•
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 \text{ V, } I_D = -250 \mu\text{A}$	-20	-23		V
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = -16 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 25^{\circ}\text{C}$			-1.0	μΑ
		$V_{DS} = -16 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 85^{\circ}\text{C}$			-5.0	1
Gate-to-Source Leakage Current	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 12 \text{ V}$			±100	nA
ON CHARACTERISTICS (Note 2)						
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_{D} = -250 \mu A$	-0.6	-0.75	-1.2	V
Drain-to-Source On- Resistance	R _{DS(on)}	$V_{GS} = -4.5$, $I_D = -2.2$ A		0.130	0.155	Ω
		$V_{GS} = -2.5$, $I_D = -1.7$ A		0.200	0.240	1
Forward Transconductance	9 _{FS}	$V_{DS} = -10 \text{ V}, I_D = -1.7 \text{ A}$		5.0		S
CHARGES AND CAPACITANCES						
Input Capacitance	C _{ISS}			185	300	pF
Output Capacitance	C _{OSS}	$V_{GS} = 0 \text{ V, f} = 1.0 \text{ MHz,}$ $V_{DS} = -10 \text{ V}$		95	150	1
Reverse Transfer Capacitance	C _{RSS}	VDS = 10 V		30	50	1
Total Gate Charge	Q _{G(TOT)}			3.0	6.0	nC
Threshold Gate Charge	Q _{G(TH)}	$V_{GS} = -4.5 \text{ V}, V_{DS} = -10 \text{ V},$ $I_D = -2.2 \text{ A}$		0.2		
Gate-to-Source Charge	Q_{GS}	$I_D = -2.2 \text{ A}$		0.5]
Gate-to-Drain Charge	Q_{GD}			0.9		
SWITCHING CHARACTERISTICS (Note	e 3)					
Turn-On Delay Time	t _{d(ON)}			7.0	12	ns
Rise Time	t _r	$V_{GS} = -4.5 \text{ V}, V_{DD} = -16 \text{ V},$		13	25	1
Turn-Off Delay Time	t _{d(OFF)}	$I_D = -2.2 \text{ A}, R_G = 2.5 \Omega$		33	50	1
Fall Time	t _f			27	40	
DRAIN-SOURCE DIODE CHARACTER	ISTICS (Note 2)					
Forward Diode Voltage	V _{SD}	V _{GS} = 0 V, I _S = -2.1 A		-0.85	-1.15	V
Reverse Recovery Time	tRR			32		ns
Charge Time	ta	$V_{GS} = 0 \text{ V, } I_{S} = -2.1 \text{ A},$		10]
Discharge Time	tb	dl _S /dt = 100 A/μs		22		
Reverse Recovery Charge	QRR]		15		nC

SCHOTTKY DIODE ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise noted)

Parameter	Symbol	Test Conditions	Min	Тур	Max	Units
Maximum Instantaneous Forward Voltage	V_{F}	I _F = 0.1 A		0.425		V
		I _F = 0.5 A		0.480		
		I _F = 1.0 A		0.510	0.575	
Maximum Instantaneous Reverse Current	I _R	V _R = 10 V			1.0	μΑ
		V _R = 20 V			5.0	
Maximum Voltage Rate of Change	dv/dt	V _R = 20 V		10,000		V/ns
Non-Repetitive Peak Surge Current	I _{FSM}	Halfwave, Single Pulse, 60 Hz			23	Α

Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2%.
 Switching characteristics are independent of operating junction temperatures.

TYPICAL MOSFET PERFORMANCE CURVES (T_J = 25°C unless otherwise noted)

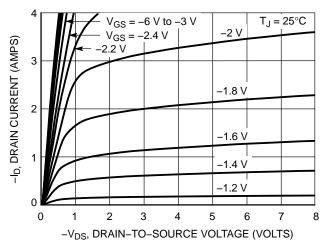


Figure 1. On-Region Characteristics

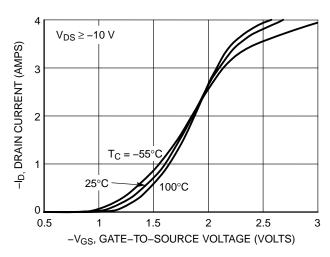


Figure 2. Transfer Characteristics

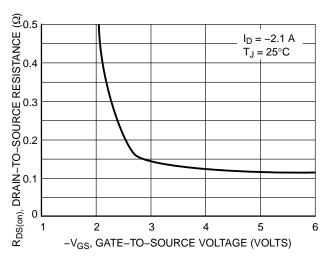


Figure 3. On-Resistance vs. Gate-to-Source Voltage

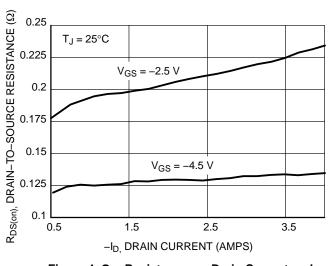


Figure 4. On–Resistance vs. Drain Current and Gate Voltage

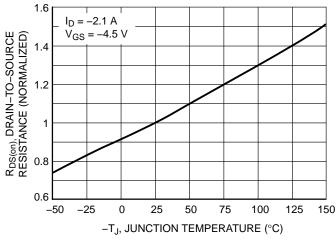


Figure 5. On–Resistance Variation with Temperature

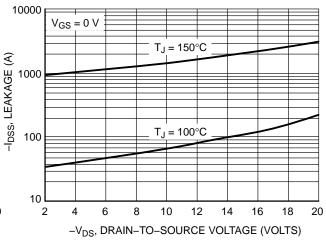


Figure 6. Drain-to-Source Leakage Current vs. Voltage

TYPICAL MOSFET PERFORMANCE CURVES ($T_J = 25^{\circ}C$ unless otherwise noted)

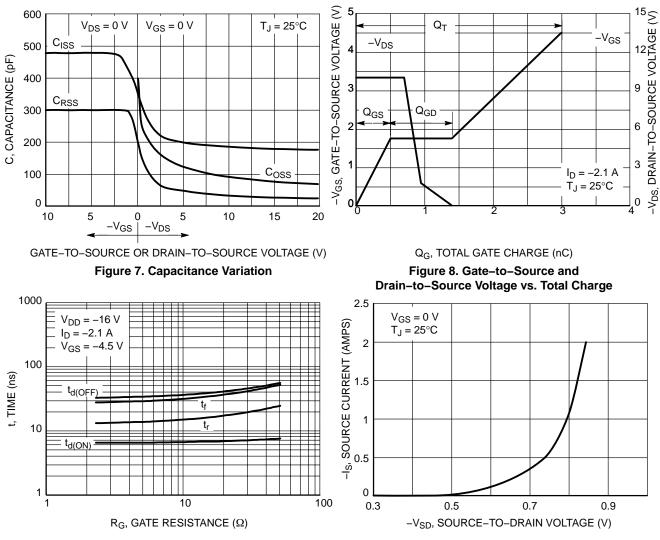


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

Figure 10. Diode Forward Voltage vs. Current

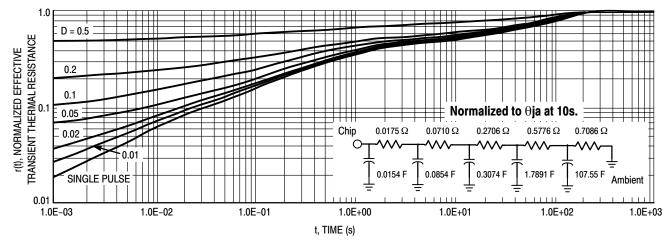
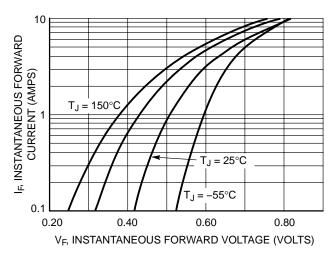


Figure 11. Thermal Response

TYPICAL SCHOTTKY PERFORMANCE CURVES (T $_{J}$ = 25°C unless otherwise noted)



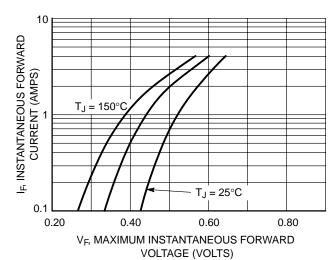


Figure 12. Typical Forward Voltage

Figure 13. Maximum Forward Voltage

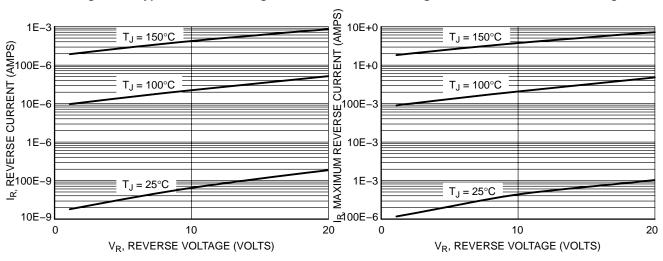


Figure 14. Typical Reverse Current

Figure 15. Maximum Reverse Current

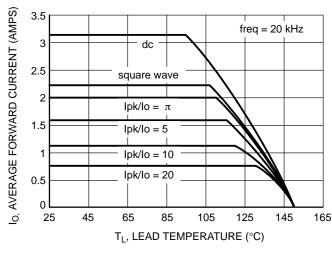


Figure 16. Current Derating

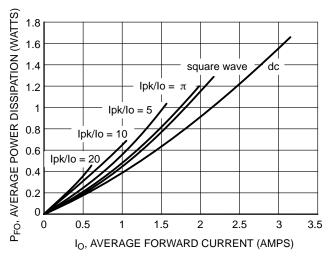


Figure 17. Forward Power Dissipation

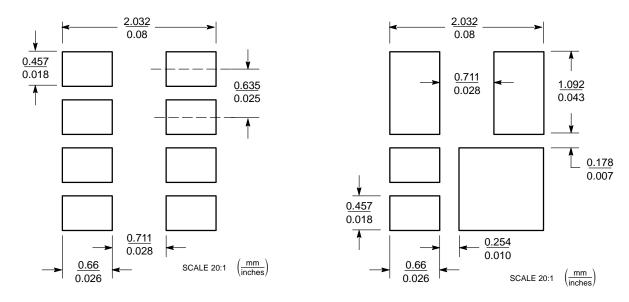


Figure 18. Basic

Figure 19. Style 3

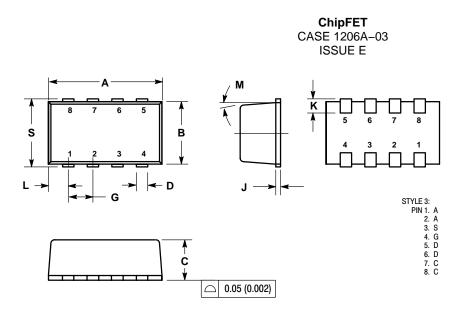
BASIC PAD PATTERNS

The basic pad layout with dimensions is shown in Figure 18. This is sufficient for low power dissipation MOSFET applications, but power semiconductor performance requires a greater copper pad area, particularly for the drain leads.

The minimum recommended pad pattern shown in Figure 19 improves the thermal area of the drain connections (pins 5, 6) while remaining within the confines

of the basic footprint. The drain copper area is 0.0019 sq. in. (or 1.22 sq. mm). This will assist the power dissipation path away from the device (through the copper lead–frame) and into the board and exterior chassis (if applicable) for the single device. The addition of a further copper area and/or the addition of vias to other board layers will enhance the performance still further.

PACKAGE DIMENSIONS



NOTES:

- NOTES:

 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
 2. CONTROLLING DIMENSION: MILLIMETER.
 3. MOLD GATE BURRS SHALL NOT EXCEED 0.13 MM PER SIDE.
 4. LEADFRAME TO MOLDED BODY OFFSET IN HORIZONTAL AND VERTICAL SHALL NOT EXCEED 0.08 MM.
 5. DIMENSIONS A AND B EXCLUSIVE OF MOLD GATE BURRS.
 6. NO MOLD FLASH ALLOWED ON THE TOP AND BOTTOM LEAD SURFACE.
 7. 1206A-01 AND 1206A-02 OBSOLETE: NEW STANDARD IS 1206A-03.

	MILLIN	IETERS	INCHES		
DIM	MIN	MAX	MIN	MAX	
Α	2.95	3.10	0.116	0.122	
В	1.55	1.70	0.061	0.067	
C	1.00	1.10	0.039	0.043	
D	0.25	0.35	0.010	0.014	
G	0.65	BSC	0.02	5 BSC	
J	0.10	0.20	0.004	0.008	
K	0.28	0.42	0.011	0.017	
L	0.55	BSC	0.022 BSC		
M	5°	NOM	5 ° NOM		
S	1.80	2.00	0.072	0.080	

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